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12/05/01

PATENT NUMBER and  
ISSUE DATE

## U.S. UTILITY Patent Application

APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10005637	12/05/2001	250	2512	2878	LE

## \*\*APPLICANTS:

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## \*\*CONTINUING DATA VERIFIED:

## \*\* FOREIGN APPLICATIONS VERIFIED:

JAPAN 2000-377116 12/12/2000

PG-FUB DO NOT PUBLISH ☐RESCIND ☐

Foreign priority claimed

☐ yes ☐ no

35 USC 119 conditions met

☐ yes ☐ no

Verified and Acknowledged Examiners's initials

ATTORNEY DOCKET NO

M2013-43

TITLE : Defect inspection method for three-dimensional object

U.S. DEPT. OF COM. / PAT. &amp; TM. PTO-135L (Rev. 12-94)

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
		Total Claims	Print Claim for O.G.
ISSUE FEE		DRAWING	
Amount Due	Date Paid	Sheets Drawn	Figs. Drawn
			Print Fig.
		Application Examiner	
<input type="checkbox"/> TERMINAL DISCLAIMER		PREPARED FOR ISSUE	
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